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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/672,223	09/27/2000	Yun-Sang Lee	AB-1043 US	6183

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[REDACTED] EXAMINER

WHITTINGTON, ANTHONY T

[REDACTED] ART UNIT

[REDACTED] PAPER NUMBER

2133

DATE MAILED: 03/05/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)
	09/672,223	LEE, YUN-SANG <i>(D)</i>
Examiner	Art Unit	
Anthony T Whittington	2133	

-- The MAILING DATE of this communication appears on the cover sheet with the corresponding address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1) Responsive to communication(s) filed on 24 December 2002.

2a) This action is FINAL. 2b) This action is non-final.

3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4) Claim(s) 1-4 is/are pending in the application.

4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5) Claim(s) _____ is/are allowed.

6) Claim(s) 1-4 is/are rejected.

7) Claim(s) _____ is/are objected to.

8) Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9) The specification is objected to by the Examiner.

10) The drawing(s) filed on _____ is/are: a) accepted or b) objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

11) The proposed drawing correction filed on _____ is: a) approved b) disapproved by the Examiner.
If approved, corrected drawings are required in reply to this Office action.

12) The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. §§ 119 and 120

13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a) All b) Some * c) None of:

1. Certified copies of the priority documents have been received.

2. Certified copies of the priority documents have been received in Application No. _____.

3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
a) The translation of the foreign language provisional application has been received.

15) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

Attachment(s)

1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892)	4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s). _____ .
2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)	5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)
3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449) Paper No(s) _____ .	6) <input type="checkbox"/> Other: _____ .

DETAILED ACTION

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-4 are rejected under 35 U.S.C. 102(b) as being anticipated by Surlekár (U.S. 5,668,764).

As per claim 1, Surlekár teaches an integrated circuit that comprises all the elements of the instant application. Surlekár teaches a plurality of internal circuits (row and column address buffers, 11 and 12) that generates internal signals (address signals) used for addressing storage locations in Figure 1. Surlekár teaches a selection circuit (35) for controlling transfer paths of the internal signals (signals from input/output lines) and data in response to selection signals (select local input/output amplifier) in Figure 3. Surlekár teaches a data output buffer (16) for transferring the internal signals (data signals) to an outside of the device through data input/output pads (data in register and data out register, 17 and 18) in Figure 1.

As per claim 2, Surlekár teaches an integrated circuit that comprises all the elements of the instant application. Surlekár teaches a plurality of internal circuits (row and column address buffers, 11 and 12) that generates internal signals (address signals) used for addressing storage locations in Figure 1. Surlekár teaches a first selection circuit (35) for receiving the internal signals (signals from input/output lines) in response to selection signals (select local input/output

amplifier) in Figure 3. Surlekar teaches a second selection circuit (multiplexer, 47) for receiving output signals from the first selection circuit (35, Figure 3) and output signals from a sense amplifier (33, Figure 3). Surlekar teaches a data output buffer (16) for transferring the internal signals (data signals) to an outside of the device through data input/output pads (data in register and data out register, 17 and 18) in Figure 1.

As per claim 3, Surlekar teaches a method for monitoring internal signals in an integrated circuit device having input/output pads (data in register and data out register, 17 and 18, Fig.1) that comprises all the steps of the instant application. Surlekar teaches detecting a test mode in column 4, lines 34-45, which state: “In the typical operation of a DRAM memory unit... During a non-test operation cycle... bits are selected and applied to the output terminal.” The determination of the operation (test mode or non-test mode) expresses that there is detection for the test mode. Surlekar teaches selecting a part of internal signals (signals from input/output lines) of the integrated circuit device in Figure 3. Surlekar teaches transferring the part of the internal signals (data signals) to an outside of the integrated circuit device through the input/output pads (data in register and data out register, 17 and 18) in Figure 1.

As per claim 4, Surlekar teaches a method for monitoring internal signals in an integrated circuit device a having sense amplifier (33, Fig. 3), a data output buffer (16, Fig 1), and input/output pads (data in register and data out register, 17 and 18, Fig. 1) comprising all the steps of the instant application. Surlekar teaches detecting a test mode in column 4, lines 34-45, which state: “In the typical operation of a DRAM memory unit... During a non-test operation cycle... bits are selected and applied to the output terminal.” The determination of the operation (test mode or non-test mode) expresses that there is detection for the test mode. Surlekar teaches

selecting a part of internal signals (signals from input/output lines) of the integrated circuit device in Figure 3. Surlekar teaches selecting an alternative one of transfer paths (multiplexer, 47, Fig. 5) of the part of the internal signals (expected data signal) and output signals from the sense amplifier (33, Fig. 3). Surlekar teaches transferring the part of the internal signals (data signals) to an outside of the integrated circuit device through the data output buffer (16, Fig. 1) input/output pads (data in register and data out register, 17 and 18) in Figure 1.

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. The following patents are cited to further show the state of art with respect to internal state monitoring in general:

U.S. Pat No. 6,272,588 to Johnston et al.

U.S. Pat No. 5,495,487 to Whetsel,Jr.

U.S. Pat No. 5,396,499 to Urai

U.S. Pat No. 5,463,635 to Kumazawa et al.

U.S. Pat No. 6,016,560 to Wada et al.

U.S. Pat No. 5,706,235 to Roohparvar et al.

U.S. Pat No. 4,144,536 to Ardezone et al.

U.S. Pat No. 4,875,003 to Burke

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Anthony T Whittington whose telephone number is 703-306-5617. The examiner can normally be reached on Monday-Friday 7:30a.m.-4:00p.m..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert Decady can be reached on 703-305-9595. The fax phone numbers for the organization where this application or proceeding is assigned are 703-746-7239 for regular communications and 703-746-7238 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-305-3900.


A.W.
February 25, 2003


ALBERT DECADY
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